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CHARGE OR PARTICLE SENSING**FIELD OF THE INVENTION**

5 The invention relates to a sensing arrangement, a detection system, a macropixel and a method of detecting the arrival of one or more charged particles and/or one or more quanta of electromagnetic radiation.

BACKGROUND OF THE INVENTION

10 Conventional pixel radiation sensors are often based on a hybrid approach in which an electronic circuit is bump bonded to a pixel sensor.

There are a number of types of conventional semiconductor imagers and sensors. One class is based on a hybrid pixel sensor arrangement for two-dimensional single particle detection, or single photon detection. Another class
15 uses monolithic active pixel sensors (APS) that are solid state imagers that provide, for each pixel, radiation-sensing, charge-to-voltage conversion, and a reset function.

The hybrid pixel sensor arrangement is mainly used for IR focal planes, Silicon
20 Pixel arrays for single particle detection, X-ray detection and medical imaging. The hybrid pixel sensor permits independent optimisation of the radiation detector characteristics and the pixel readout electronics because they are fabricated on two separate substrates with two different processes. However, this type of pixel sensor has a limit to the minimum achievable pixel
25 dimensions due to the bump bonding technique. So far 50µm x 50µm has been achieved, but it is expensive and complex to fabricate. Moreover, the hybrid

pixel sensor has an input capacitance (100fF to 200fF) sufficiently high to limit the operation and noise performance.

Monolithic APS devices are mainly used for visible light imaging together with
5 CCD imagers, but have also been applied for single particle detection. Known
monolithic APS devices employ a floating diffusion as a pixel sensor in the
form of an n-diffusion/n-well in p-doped silicon substrate, a photo-gate, or a
PIN diode formed in amorphous Si:H deposited above the integrated circuit. In
these devices, the pixel signal current is integrated using the input capacitance
10 during an integrating time period of a few milliseconds. The integrated current
is read out by a source follower MOSFET transistor F1 as shown in Figure 1
(prior art). Pixel select transistor F3 switches the output of the pixel to a
common load F4. The floating node which comprises the junction of the gate
of the source follower MOSFET transistor F1, the pixel sensor and the drain of
15 F2, is sequentially reset by a reset MOSFET transistor F2. This has the
disadvantage of generating kTC or reset noise far above the intrinsic electronic
noise of the amplifier stage. Furthermore, the device shown in Figure 1 is not
capable of discriminating between incident quanta (hits) during the integration
period.

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For single charged particle detection, the conventional monolithic APS uses, as
the sensor element, an 8-12 ohm epitaxial layer of the silicon wafer used in
standard commercial CMOS technologies, the layer being a few microns thick.
The charge signal collected is, for example, of the order of 80 e- for a minimum
25 ionising charged particle traversing a 1µm thick silicon layer. A major
drawback of the conventional bulk silicon sensor is that charge collection is
achieved by thermal diffusion of carriers. This intrinsically limits carrier

velocity and thus charge collection is slow> Charge collection is also spread over adjacent pixels and not complete.

For single photon detection using an integrated APS with an avalanche gain of, for example, 50, the collected charge per photon may be 50 e-. For such very low signal levels, conventional APS architecture is only marginally usable, if at all, as the signal-to-noise ratio required to detect one visible photon, one X-ray or one charged particle is desirably at least 10 to minimise background noise. This requires a noise floor below 5 e- rms, which cannot be achieved by the conventional APS integrating architectures. These architectures have a conversion gain in the order of 20 $\mu\text{V}/\text{e-}$ and a reset noise level of greater than 10 e- rms.

Moreover, the integrating APS architecture of conventional devices cannot measure the timing of particle events, and cannot digitally count each incoming charged particle or X-ray or visible photon. Conventional circuit architectures for hybrid pixel radiation sensors are generally too large, typically, at best 50 μm x 50 μm , and consume too much power, for example 30 to 50 μW , and are consequently not usable for monolithic integration of high density pixel sensors with quantum detection capability. The applicant is not aware of circuitry able to process the very low signals required for Single Particle/Photon Detection and imaging (SPD) in monolithic integrated circuits.

The present invention aims to substantially overcome or ameliorate one or more of the aforementioned problems.

In particular, embodiments of the present invention address problems of monolithic integration of active silicon pixels in commercial deep submicron CMOS technologies. Embodiments aim to achieve single particle detection, spatial localisation of single charged particle tracks and single photon detection
5 in contrast to conventional APS designs which integrate the sensor signal current over a certain integrating time period.

SUMMARY OF THE DISCLOSURE

10 According to a first aspect of the present invention there is provided a sensing arrangement having a sensor device and amplifier circuitry, the sensor device being constructed and arranged to provide a sensor signal when it receives or one or more charged particles and/or one or more quanta of electromagnetic radiation, the amplifier circuitry having an input node and an output node, the
15 sensor device being connected to said input node for supplying said signal thereto whereby the level at the output node changes, and further having feedback circuitry connecting said input node and said output node for feeding back a portion of the level at the output node for maintaining a first level at the output node in the absence of a said signal from said sensor device, the
20 feedback device being responsive to the change in level of said output node to vary the effect of said feedback circuitry when said level changes to increase the loop gain of said amplifier circuitry.

25 According to a second aspect of the invention there is provided a sensing arrangement having a sensor device and amplifier circuitry, the sensor device being constructed and arranged to provide a sensor signal when it receives or one or more charged particles and/or one or more quanta of electromagnetic

radiation, the amplifier circuitry having an input node and an output node, the sensor device being connected to said input node for supplying said signal thereto whereby the level at the input node changes and causes an output signal from said output node, the arrangement further comprising a current mirror
5 connected to said input node and constructed and arranged to supply current thereto for restoring the level at the input node to a starting level.

According to the present invention in a further aspect there is provided a sensing device comprising a sensor for detecting arrival of an incident quantum
10 of electromagnetic radiation and/or charged particles, and an amplifier connected to the sensor for amplifying a signal from the sensor, wherein the sensor and the amplifier are fabricated on a common substrate, the sensing device being arranged to discriminate between the arrival of single or multiple incident quanta at the sensing device.

15 The sensor and the amplifier may be diffused onto the common substrate, or are deposited on the common substrate. The sensing device may be a pixel cell.

The substrate may comprise a monolithic semiconductor integrated circuit
20 substrate and the sensor comprises a p-n junction sensor overlaying the substrate, a p-n photodiode, an avalanche photodiode integrated in the substrate, or a radiation sensor for detecting charged particles and/or X-ray photons.

In one embodiment, the substrate comprises a silicon crystal bulk into which the
25 sensor and amplifier are introduced.

The sensing device may comprise an amorphous Si:H PIN diode having a plurality of amorphous Si:H layers comprising an N doped layer, an Intrinsic layer, and a P doped layer, the layers being deposited above the substrate. In an alternative embodiment, the sensing device further comprises an amorphous selenium layer, the amorphous selenium layer being deposited above the substrate. The use of an amorphous selenium layer is particularly advantageous in X-ray applications, such as mammogram procedures. It has a higher conversion efficiency for X-ray photons of energy above 10 KeV than that provided when amorphous Si:H is used.

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The amplifier may be implemented as a non-linear transresistance amplifier.

The sensor and the amplifier may be diffused onto the substrate or deposited onto the substrate.

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According to the present invention in yet another aspect there is provided a device for producing a signal corresponding to a detection event comprising one or more of the sensing devices defined above, further comprising a readout circuit for receiving the output of one or more of the sensing devices and producing an output signal corresponding to the detection event.

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The device may further comprise a detection plane array of the sensing devices defined above.

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In an embodiment, the readout circuit is a complementary metal oxide semiconductor (CMOS) circuit formed on the substrate and the substrate may be of a first conductivity type, the CMOS circuit comprising one or more metal

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oxide field effect transistors of a first conductivity type, a well region of a second conductivity type in said substrate, and one or more metal oxide semiconductor transistors of a second conductivity type formed in the well region.

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The readout circuit may comprises a first section and a second section. The first section may comprise a non-linear transresistance amplifier.

10 In an embodiment, the non-linear transresistance amplifier comprises a transconductance amplifier, a feedback field effect transistor, and an input current source.

15 The second section may comprise a transistor discriminator for generating a binary signal for each quantum of electromagnetic energy and/or charged particle detected.

The device may be is arranged to detect each quantum impinging upon each sensing device, providing Single Particle Detection (SPD).

20 The device may be arranged to integrate charges and sequentially reading the charges out for standard APS operation.

25 The sensor may be a p-n sensor or p-i-n sensor, and the amplifier have an input sensing node, the input sensing node being connected to the drain of the feedback field effect transistor, the electrode of the sensor and the drain of the input current source.

The readout circuit may have an output current, and the readout circuit be arranged to receive external reference signals, the external reference signals comprising a voltage reference, a current reference, and a bias current, wherein the external reference signals and the output current from the readout circuit are common to the one or more sensing devices.

The feedback field effect transistor may have its source connected to the output of the transconductance amplifier.

In an embodiment, the feedback field effect transistor is arranged such that the feedback field effect transistor has a drain current equal to a reference current mirrored by the input current source when the feedback field effect transistor is biased in weak inversion, the field effect transistor forming the input current source, and the feedback field effect transistor DC biasing the sensor.

The feedback field effect transistor may be arranged such that when biased at a low current between around 1-20pA the current decreases when an input signal occurs at the input sensing node by a particle or photon impinging on the p-n or p-i-n sensor.

The transconductance amplifier may be in closed-loop when said feedback field effect transistor operates as a feedback network and has a drain current above zero.

In an embodiment, the transconductance amplifier is arranged to operate like a transresistance stage with the feedback field effect transistor operating as a feedback network.

The feedback field effect transistor may be arranged such that when the feedback field effect transistor turns off for an input signal charge above a threshold value the feedback field effect transistor has a drain current of about zero.

The quantum may provide an input charge to the sensor, wherein the input threshold charge is around 10 to 15 e- at a reference current of around 10pA.

The non-linear transresistance amplifier may be arranged to be in open loop when the feedback field effect transistor turns off for an input signal above threshold.

The non-linear transresistance amplifier may have a low gain for small input signals below threshold when the feedback transistor is turned on, and the non-linear transresistance amplifier has a large gain for signals above threshold when the feedback transistor is turned off.

In an embodiment, the discriminator transistor has its gate connected to the output of the amplifier, and its drain connected to the output of the sensing device, the output port of the sensing device being connected to the output signal, the output signal being a current.

The readout circuit may be arranged to receive a voltage reference, the voltage reference establishing the voltage of the output node of the transconductance amplifier through gate-to-source voltage of the feedback transistor.

The voltage reference may be arranged to bias the transistor discriminator in weak inversion at a drain current of few nanoamps.

5 The quantum may impinge on one or more of the sensing devices generating a voltage across the sensor forming an input sensing node voltage, the input sensing node voltage decreasing and output voltage of the transconductance amplifier increasing when the quantum impinges on one or more of the sensing devices.

10 The device may be arranged such that when a voltage increases of the output node of the transconductance amplifier occurs, the drain current of the discriminator transistor increases as the exponential of the voltage variation of the output voltage of the transconductance amplifier.

15 The drain current increase of the discriminator transistor may be 1000 times (3 current decades) its value between around 1nA to 1 μ A for an output voltage increase of the transconductance amplifier of about 250 mV.

20 The current drain increase of the transistor discriminator may switch the voltage of the output port of the sensing device and generates a binary signal.

An output voltage increase of about 250 mV may be generated by an input charge of about 25 e^- .

25 The readout circuit may be arranged to receive a voltage reference giving a voltage reference value, the voltage reference value determining the standby

current of the discriminator transistor to provide a discrimination threshold of the readout circuit.

5 The readout circuit may comprise an integrating active pixel sensor (APS) imager.

The integrating imager may include a source follower stage in place of a discriminator transistor.

10 The integrating imager may have an input current source, the input current source being switched off during integrating time and readout time.

The input current source may be periodically biased at about 10pA during the reset time.

15 The device may be arranged such that the feedback transistor switches off when the input signal rises above threshold to open the loop around the amplifier to cause a large increase in gain of the amplifier and thereby heighten the sensitivity of the one or more sensing devices.

20 The amplifier may comprise a non-linear amplifier having an output and an input, the amplifier being arranged to have a feedback capacitance minimised to around 10^{-17} F for obtaining a charge-to-voltage conversion gain of about 5mV to 10mV at its output for each electron entering its input.

25 The device may be an imaging device for producing an output signal corresponding to a detected image.

According to the present invention in yet another aspect, there is provided a macro-pixel comprising an array of sensing devices defined above, wherein the outputs of the sensing devices are combined to give the effect of a larger pixel. The outputs of the pixels may be connected to a bus. The macropixel may be
5 configured such that if a sensing device in the macropixel should fail, the macropixel will continue to be operable but at a reduced sensitivity.

According to the present invention in a still further aspect there is provided an array of macropixels defined above connected to detect or form an image.

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According to a yet further aspect of the invention there is provided a device comprising an array of the macropixels defined above wherein the imaging device is diffused into or deposited onto the surface of a wafer.

15 The invention, in one or more embodiments, is applicable to semiconductor imaging and radiation detection devices, in particular to monolithic silicon active pixel sensor arrays capable of detecting single photons or particles, such as visible light, X-rays, and charged particles such as electrons or protons. The monolithic approach allows fabrication in a standard CMOS process.

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In an embodiment, the invention is embodied in an imaging device formed as a monolithic, complementary metal oxide semiconductor integrated circuit in an industrial standard metal oxide process. The pixel integrated circuit may include an amorphous Si:H PIN diode for collecting single photon/particle-generated charge deposited above the integrated circuit overlying the substrate,
25 or an n-well junction or other diode in an underlying region of the epitaxial layer and bulk substrate. The pixel integrated circuit also may include, a readout

circuit having at least a transconductance amplifier, and an N-MOSFET feedback device in the p-doped substrate. The N-MOSFET feedback device may be connected between the sensing node formed by the connection of the input of the transconductance amplifier with the pixel sensor electrode and the output node of the transconductance amplifier.

In an embodiment, the transconductance amplifier is a four-device circuit formed by two P-MOSFET transistors and two N-MOSFET transistors. In this embodiment, the two P-MOSFET transistors operate as a high gain input cascode amplifier circuit with the input gate connected to the sensor element which could be an N-well electrode, or the PIN amorphous Si:H diode. The two N-MOSFET transistors operate as a high impedance cascode output current source. This embodiment includes an N-MOSFET feedback device that is biased in deep weak inversion by an additional input current source P-MOSFET, which forms, together with a diode connected P-MOSFET, a current mirror that is biased by an external current source.

The feedback MOSFET transistor may be biased to a sufficiently low current, for example between 1pA to 20pA, to enable it to be switched off when a small input signal charge of 1 e- to 20 e- arrives at the input. The four MOSFET transistor cascode amplifier may operate in open loop once the feedback MOSFET transistor is switched off by the input signal. The output N-MOSFET discriminator transistor may sense the voltage of the output node with its gate connected to the output node, its drain connected to an external current source, and its source connected to the ground. An external voltage V_{REF} may control the voltage of the output node of the cascode transconductance amplifier and determines the operating conditions of the output N-MOSFET discriminator

transistor. The voltage V_{REF} may be chosen in such a way that the output MOSFET transistor is biased in the sub-threshold region (which is also termed weak inversion) and switches on when an input charge signal occurs thereby moving the output node of the discriminator transistor from the supply voltage VDD to ground. The dimensions of the input P-MOSFET transistors may be sized for minimum noise compared with the N-well diffusion capacitance, or the PIN amorphous Si:H diode capacitance.

The N-MOSFET transistors of the output current source may be dimensioned and laid out for minimum drain capacitance. The parasitic capacitance between the input node and the output node of the amplifier may be minimised in order to maximise the open loop gain of the amplifier branch. The amplifier may be biased with a low current to keep the power consumption of the pixel cell below 250nW. The readout circuit may further include a fast OR-line connecting together a group of pixels. The group of pixels forms a macropixel that is read out by the peripheral readout of the integrated circuit. Each macropixel may have a driver circuit that interfaces with the readout of the end-of-column logic circuit.

In an embodiment, there is provided an analogue output for summing signals inside a macropixel. In another embodiment, the invention is arranged to have high gain signal integration for very sensitive APS applications in which the reference current is controlled to perform a soft pixel reset without kTC reset noise.

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BRIEF DESCRIPTION OF THE DRAWINGS

Embodiments of the invention will now be described, by way of example only, with reference to the accompanying drawings in which:-

5 FIG 1 is a circuit diagram illustrating the architecture of a prior art APS circuit;

FIG 2A is a schematic circuit diagram of a sensing device, embodying the invention;

10 FIG 2B is a schematic circuit diagram corresponding to FIG 2A, illustrating an open-loop condition with polarity inversion across a feedback transistor of an amplifier thereof;

15 FIG 3 is a schematic circuit diagram illustrating a binary circuit of an individual sensing device embodying the invention;

FIG 4 is a schematic circuit diagram of a circuit for reading the outputs of a plurality of sensing devices,;

20 FIG 5 is a graph of waveforms showing the transition from closed-loop to open-loop operation of an amplifier of Figures 2A, 2B and 3;

FIG 6 is a graph of waveforms of the input sensing node, output transconductance amplifier node and output of a transistor discriminator of the pixel shown in Figures 2A, 2B and 3 for input charges of 12.5 e-, 25 e-, 50 e- and 100 e-;

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FIG 7 is a graph of the waveforms of the output transconductance amplifier node of the sensor, for example a pixel, shown in Figures 2A to 3 for an input charge of 75 e- and input current of 1pA, 2pA, 5pA, 10pA and 20pA;

5 FIG 8 is a graph of the variation of the source voltage with the drain current at a constant gate voltage of a feedback MOS transistor working in weak inversion as used in Figures 2A to 3;

10 FIG 9a is a graph of the noise calculation as function of the input-sensing node capacitance of the Single Particle Detection sensing device, such as a pixel cell, shown in Figures 2A to 3;

FIG 9b is a graph of the noise calculation as function of reference current of the SPD sensing device shown in Figures 2A to 3;

15 FIG 10 is a schematic diagram of the architecture circuit for a charge integrating device embodying the invention;

20 FIG 11 is a graph of the input current, one electron every 500ns, of the input node and of the output node of the integrating sensing device of Figure 10;

FIG 12 is a graph of the noise (ENC) as a function of the operating temperature, from 77K to 297K of the binary sensing device, for example pixel, circuit of Figure 3;

25 FIG 13 is a graph of the binary sensing device circuit of Figure 3 for 1.5fF sensor capacitance set to detect 3 electrons charge;

FIG 14 is a view of a macropixel arrangement grouping together 16 pixels of the type shown in Figure 3;

FIG 15 is a cross-section of a sensor ASIC assembly into which the pixel of
5 Figures 2A to 4, and 10 may be diffused with an amorphous Si:H PIN sensor deposited on the surface of the ASIC;

FIG 16a is a block schematic diagram of an array of 64 pixels of the type shown
10 in FIG 3;

FIG 16b is an array of 64 pixels of the type shown in Figure 3 arranged in an 8x8 matrix and forming a macropixel that may be read out with an analogue multiplexing APS readout scheme;

FIG 17 is a large area sensor such as a complete wafer carrying an assembly of
15 arrays of the type shown in Figures 4, 16a and 16b; and

FIG 18 shows an avalanche photodiode structure integrated on a silicon substrate using a CMOS process for use in the invention.

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DETAILED DESCRIPTION OF THE EMBODIMENTS

In the various figures, like reference signs refer to like parts.

25 Figure 2A shows a simplified schematic block diagram of one sensing device 10, such as a pixel cell, of a Single Particle Detector (SPD) planar array of many such devices, or cells, formed in an integrated circuit. The sensing device

10 has a sensor 12, an inverting transconductance amplifier 14, a current mirror formed from two transistors T2 and T3, a feedback MOSFET transistor T1, and an output MOSFET discriminator transistor T4. The sensor 12 is connected to the input of the amplifier 14. The feedback MOSFET transistor T1 has its main
5 current path connected between the input and the output of the amplifier 14 and the output of the amplifier 14 is fed to the output MOSFET discriminator transistor T4, and is configured to be able to provide negative feedback. The discriminator transistor T4 is driven directly from the output node of the transconductance amplifier 14. The transistor T4 acts as a switch, remaining off
10 until its gate voltage reaches the threshold voltage of the transistor, so that the output I_{OUT} remains at zero until that threshold is exceeded, thus providing a binary output. The total capacitance C_f between the input node and the output node of the amplifier 14 is the sum of the parasitic capacitance between the input node and the output node added to the drain-to-source capacitance of the
15 feedback transistor T1.

A number of different sensors and sensor types may be used. Among these are a pixel sensor comprising an N-well diffusion working in linear or avalanche regime, a PIN amorphous silicon sensor deposited onto the substrate, a p-n
20 photodiode, an avalanche photodiode integrated in the substrate, a radiation sensor for detecting charged particles and/or X-ray photons or a PIN amorphous Si:H diode (in the case of the amorphous-silicon-thin-film-above-integrated-circuit implementation). The sensor may include any high atomic number X-ray detecting material deposited on or over the substrate, specific examples
25 being mercuric iodide, lead iodide, and amorphous selenium, for example forming a pin diode. Another alternative sensor is an avalanche photodiode integrated on the silicon substrate, as shown in Figure 18.

An input current source I_{REF} 18 is mirrored by the current mirror comprising the diode-connected MOSFET transistor T3 and transistor T2.

- 5 In the embodiment illustrated in Figure 2A, the current source 18 (I_{REF}) injects current via the current mirror T2,T3, into the feedback MOSFET transistor T1. The typical range value of I_{REF} is between 1pA to 20pA biasing the feedback MOSFET transistor T1 deeply in weak inversion. The source of the feedback MOSFET transistor T1 causes the potential of the output V_{OUT} of the
- 10 transconductance amplifier 14 to be governed by the gate voltage V_{REF} . The precise potential value of the output node is:

$$V_{OUT} = \frac{V_{REF}}{n} - U_T \text{Log} \left[\frac{I_{REF}}{2n\mu C'_{ox} \frac{W}{L} U_T^2} \right]$$

- The value of the reference voltage V_{REF} is chosen such that the potential V_{OUT} of
- 15 the output node is held lower than the potential of the input node V_{IN} . This biases the feedback MOSFET transistor T1 to have a positive drain-to-source voltage sufficient to operate it in saturation.

- The DC input voltage V_{IN} is determined by the operating condition of the input
- 20 circuit of the transconductance amplifier 14. Typically this will be a MOSFET amplifier, and the DC level is then typically the supply voltage VDD minus the gate-to-source voltage of a MOSFET transistor serving as input transistor of the amplifier 14.

- Each electromagnetic radiation quantum impinging on the substrate and
- 25 epitaxial layer in the vicinity of the p-n junction formed in the sensor 12

generates a packet of electron-hole pairs (typically $80 \text{ e}^- \text{ h pairs}$ for $1 \mu\text{m}$ thick silicon layer). The electron charge packet ΔQ_{DET} then drifts (by thermal diffusion, or by the electric field in the case of the amorphous-silicon-thin-film-above-integrated circuit implementation) and is collected in the sensor 12, thereby building up a negative voltage step $-\Delta V_{IN}$ at the input of the transconductance amplifier 14 superimposed on its DC potential V_{IN} .

The size of the voltage step ΔV_{IN} is $\frac{\Delta Q_{DET}}{C_{IN}}$, where C_{IN} is the total input capacitance including all capacitances connected to the input sensing node, which is typically $2\text{fF} - 5\text{fF}$ (around 2 for a PIN amorphous Si:H diode to 3 - 5fF for a diode sensor in the bulk material). The input voltage step ΔV_{IN} generates an output current step ΔI_{OUT} at the output of the transconductance amplifier 14.

The size of the current step is given by $\Delta I_{OUT} = -gm \Delta V_{IN}$.

The amplifier 14, by virtue of the feedback transistor T1, works initially as a transresistance amplifier and consequently the reference input current I_{REF} is mirrored in the feedback branch formed by the feedback MOSFET transistor T1. In the steady state, the feedback transistor T1 is operated in grounded gate configuration with the source as the output node and the drain as the input node.

When a hit by a particle or photon occurs, the negative voltage step $-\Delta V_{IN}$ is built up at the input of the transconductance amplifier 14 which then generates an output current step at its output $\Delta I_{OUT} = -gm \Delta V_{IN}$. This current change

produces a rising voltage ΔV_{OUT} , which decreases the feedback current from its initial value I_{REF} , to a lower value depending on the ΔV_{IN} amplitude. If this ΔV_{IN} change is sufficiently large, the drain current of the feedback MOSFET transistor T1 decreases to zero and the transconductance amplifier 14 starts to function in open-loop mode. If this variation ΔV_{IN} is instead small enough to maintain the feedback drain current greater than zero, then the transconductance amplifier loop remains closed, and continues to function as a transresistance amplifier.

10 The current I_{REF} is selected to keep the feedback transistor T1 in deep weak inversion giving an extremely low drain-to-source capacitance C_{DS} of around 5-20aF to maintain high sensitivity to an incoming a quantum or incoming quanta.

15 Where a deep submicron CMOS FET is used as the feedback transistor T1, such devices being of the order of 0.25 μ m, or smaller, and which are biased in deep weak inversion, the capacitance from drain-to-source tends to zero when the gate-to-source voltage is less than 0.4V. Under these conditions, such a feedback transistor T1 operates as a switch controlled by the input signal itself, 20 needing no additional reset facility and hence the device has no reset noise.

Figure 2B shows the sensing device, of Figure 2A in open-loop condition with the source S and the drain D of T1 interchanged compared to that shown in Figure 2A.

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In the conditions shown in Figure 2B, the threshold for the transition from closed-loop to open-loop occurs at a very small drain current of the feedback

MOSFET transistor T1. When the output voltage variation of the output node of the transconductance amplifier 14 is large enough to invert the polarity of the drain-to-source voltage of the feedback MOSFET transistor T1, the drain swaps with source, as shown in Figure 2B. The source becomes the node connected to the input sensing node. The gate-to-source voltage of the feedback MOSFET transistor T1, defined by the reference voltage V_{REF} minus the input DC voltage of the transconductance amplifier 14 -- is constant during the polarity inversion time period.

10 The OFF drain current of T1 is defined by

$$I_{Doff} = 2n\mu C_{ox} \frac{W}{L} U_T^2 e^{\frac{V_{REF} - n\Delta V_{INDC}}{nU_T}}$$

The voltage reference V_{REF} is low enough that the gate-to-source voltage of the feedback MOSFET transistor T1 keeps this OFF-drain current small enough to avoid discharging the input sensing node and the output node of the transconductance amplifier 14.

Typically, the open-loop transition of the transconductance amplifier 14 and the drain-source polarity inversion of the feedback MOSFET transistor T1 occurs for sensed input charge greater than 10 e-. In this operational mode the amplifier stage has a voltage gain defined by:

$$\frac{\Delta V_{OUT}}{\Delta V_{IN}} = -gm.R_{OUT}$$

For typical values of transconductance g_m of $10^{-5}S$, and output resistance R_{OUT} of the transconductance amplifier 14, of 10^8 to 10^9 ohms, typical open voltage gain $\frac{\Delta V_{OUT}}{\Delta V_{IN}}$ is about 1000 to 10000. Therefore, a conversion gain of 5 to 10 mV/e- may be achieved which is a value that is 3 orders of magnitude larger than those of known APS pixel cells.

For this very high gain, the rise time of the output voltage at the transconductance output node is determined by the slew rate imposed by the output current of the transconductance amplifier 14, and not by the output time constant $R_{OUT}C_{OUT}$. The output voltage rise time is governed by the equation:

$$\frac{\Delta V_{OUT}}{\Delta t} = \frac{qQ_{DET}}{nkTC_{OUT}C_{IN}} I_{BIAS}$$

where I_{BIAS} is the bias current.

Response time Δt_R is determined by the minimum detectable voltage ΔV_{MIN} seen at the input of the transistor discriminator T4 and is defined by:

$$\Delta t_R = \Delta V_{MIN} \frac{nkTC_{OUT}C_{IN}}{qQ_{DET}I_{BIAS}}$$

After an input charge event, the feedback loop remains open until the input current source 18 charges the input sensing node to its initial DC value with a time equal to about Q_{DET}/I_{REF} . This is a smooth charge, not a step event. For typical values of I_{REF} and ΔQ_{DET} of 10pA and 100 e-, the recovery time is about

1.6 microsecond. The time constant of the output node, which is shorter, is defined by $\tau_{OUT} = R_{OUT}C_{OUT}$.

For $R_{OUT} = 10^8$ and $C_{OUT} = 1fF$, the time constant is typically 100ns.

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The value of the current reference I_{REF} , adjusted externally on the periphery of the chip, determines the threshold level that triggers the open loop regime.

The feedback MOSFET transistor T1, together with the input current source 18
 10 (I_{REF}), provides automatic DC control of the potential of the input sensing node, without the need for any additional reset device. The feedback MOSFET transistor T1, together with its associated diode-strapped MOSFET transistor T3 of the current mirror T3 T2 which mirrors the current I_{REF} , also provides the control of the non-linear operation of the amplifier 14 and determines the
 15 threshold of the open-loop operation.

The value of the voltage reference V_{REF} , adjusted externally on the periphery of the chip, determines the threshold level of the output MOSFET transistor T4 which acts as a discriminator transistor. During the occurrence of an input
 20 charge ΔQ_{DET} , the gate of the output MOSFET transistor T4 senses the positive signal voltage pulse ΔV_{OUT} generated at the output of the transconductance amplifier 14, and generates an output current that quickly lowers the output node from the positive supply rail to the ground level. The output MOSFET transistor T4 works in weak inversion, and with an appropriate value of V_{REF} ,
 25 output transistor T4 works likes a discriminator. The exponential current I_{DO} rise providing the discrimination effect is governed by:

$$I_{DO} = 2n\mu C_{ox} \frac{W}{L} U_T^2 e^{\frac{V_{REF} - n\Delta V_{OUT}}{nU_T}}$$

For example, a DC drain current of transistor 30 set to 1nA by V_{REF} , and a
 5 output voltage swing ΔV_{OUT} 10 times U_T (250mV) raises the drain current 3
 orders of magnitude to 1 μ A, which is sufficient to switch the output node fed
 down to ground level with an external current source set to 0.5 μ A.

The output MOSFET transistor T4 provides a fast signal discrimination
 10 function with a threshold value between $5U_T$ to $10U_T$. Transistor T4t also
 provides a local line driver function in generating an output binary signal
 without consuming power, except when the circuit is activated by the
 occurrence of an input charge ΔQ_{DET} above its threshold.

15 Figure 3 shows a binary implementation of a sensing device, embodying the
 invention. The sensing device comprises a sensor 12, a transconductance
 amplifier having two transistors M1 and M4, a current source 18, a current
 mirror having two transistors M3 and M6, a feedback transistor M2, and an
 output stage comprising four transistors M8, M10, M11, M12, two cascode
 20 transistors M10, M8 providing output X and two cascode transistors M11, M12
 providing output Y. The sensor 12 is connected to the input of the
 transconductance amplifier M1 M4. The current source 18 is connected to the
 node of the input of the transconductance amplifier M1 M4 and the sensor 12.
 The feedback transistor M2 is connected between the input and output of the
 25 transconductance amplifier M1 M4. The output of the transconductance
 amplifier M1 M4 is connected to the output stage M10 M8 and M11 M12.

Constant current load to the output of the transconductance amplifier M1 M4 is provided by a cascode current mirror with driving diode-strapped transistor M9, and driven transistor M5 in cascode with transistor M5. The common gate transistors M7, M10 and M12 have a single gate voltage V_{CAS} . The X output
5 current is taken from the drain of common gate transistor M10 and the Y output current is taken from the drain of common gate transistor M12.

As illustrated in Figure 3, the output discriminator stage M10 M8 and M12 M11 of the sensing device consists of a cascode amplifier formed by the N-MOSFET
10 transistors M8 M10 and M11 M12. The complete dynamic operation of the circuit of Figure 3 is like that described with regard to Figures 2A and 2B above, however, the sensor 12 is connected between a bias voltage V_s and the input node V_{IN} . In embodiments where the sensor 12 is an amorphous Si:H PIN diode deposited on ASICS, V_s is selected to be in the region $-10V$ to $-300V$.
15 In embodiments where the sensor 12 is a p-n diode junction diffused on a substrate, V_s may be at ground.

The circuit of Figure 3 may also be modified for circuit compactness reasons by replacing cascode current source M5 M9 with a simple current source and the
20 cascode discriminator transistors M8 M10 with a single discriminator transistor.

In another embodiment, an analogue readout may be obtained by replacing the discriminator transistor with an output analogue buffer as illustrated in Figure
10.

The amplifier branch M1 M4 M5 M9 is biased with a drain current I_{BIAS} of about 200nA keeping power consumption at about 250nW for a power supply VDD set to 1.4V.

5 The feedback transistor consists of an N-MOSFET transistor M2 dimensioned close to minimum size and working in weak inversion in the saturation region. The transistor M2 is connected with its drain to the input node, and its source to the output node. The input current source formed by a P-MOSFET transistor M3 is biased at a drain current chosen between 1pA to 20pA by the current
10 mirror M6. M3 injects the same current in the feedback transistor M2 that provides DC feedback of the amplifier branch M1 M4 M5 M9. M3 keeps the potential of the input-sensing node V_{IN} , which is the gate of the transistor M1, automatically at the value needed to bias M1 to the drain current imposed by the cascode current source M5 M9 and provides the bias potential of the sensor.

15 Figure 4 shows a sensing array 400 comprising an array 300 of sensing devices, for example pixels, of the type shown in Figure 3 or a macropixel 290 (an array of pixels connected to act as a single sensor) connected in a matrix of m rows and n columns. The X output of each row is connected to the input of a sense
20 amplifier-comparator 410, there being one sense amplifier-comparator associated with each row. Similarly, the Y outputs of the sensing devices, which may be pixels, in each column are connected to the input of a sense amplifier-comparator 410. The sense-amplifier-comparators connected to the X outputs and the sense-amplifier-comparators connected to the Y outputs
25 asynchronously detect the presence of a hit on a sensing device, for example a pixel, by electromagnetic radiation or charged particles. The outputs of the sense amplifier-comparators 410 are encoded into a binary word in a

thermometric-to-binary encoder 420 to give the X and Y addresses/co-ordinates of the sensing device (e.g. pixel) which has received the hit. The X and Y addresses/co-ordinates are then available off-chip in the form of two digital bytes.

5

Figure 5 shows a simulation of the waveforms of the input and output nodes of the transconductance amplifier of Figures 3 (and 10) at an input charge of $25 e^-$. The input node waveform shows the drain current of transistor M2, and the output node waveform shows the output voltage V_{out} . The waveforms show the transition from closed-loop to the open-loop operation as function of reference currents of 5pA, 10pA, 20pA, and 50pA, as simulated with SPICE™ for a $0.25\mu\text{m}$ CMOS technology. The current I_{BIAS} and the voltage V_{REF} is constant and the same for all simulations.

15 Figure 6 is a graph of the waveforms of the output of the discriminator transistors and the output transconductance amplifier node for input charges of $12 e^-$, $25 e^-$, $50 e^-$ and $100 e^-$, as applied at V_{out} of Figures 3 (and 10), as simulated with SPICE™ for a $0.25\mu\text{m}$ CMOS technology.

20 Figure 7 is a graph of the voltage waveforms of the output transconductance amplifier node for an input charge of $50 e^-$ and input current of 2pA, 5pA, 10pA, 20pA, and 50pA, as applied at V_{out} of Figures 3 (and 10), as simulated with SPICE™ for a $0.25\mu\text{m}$ CMOS technology.

25 Figure 8 is a graph of the variation of the source voltage with the drain current at a constant gate voltage of an MOS feedback transistor working in weak inversion in the pixels shown in Figures 2A, 3 and 10.

Figure 9a is a graph of the calculated noise of the SPD pixel cell shown in Figures 2A to 3, and 10 as function of the capacitance at the input-sensing node.

Figure 9b is a graph of the calculated noise of the SPD pixel cell shown in
5 Figures 2A to 4 as function of reference current I_{ref} .

In another embodiment, as shown in Figure 10, the integrating architecture circuit of an individual sensing device is illustrated for operation in standard
10 APS imaging mode. This embodiment is applicable to conventional APS imagers where charges are sequentially integrated in sensing devices (e.g. pixel cells) and sequentially read out by column with an analogue multiplexer performing the readout operation.

The sensing device 100 of Figure 10 comprises a sensor 12, a transconductance
15 amplifier comprising two p-type transistors M1 M4 in cascode. The transistors together with feedback MOSFET transistor M2, and an input current source 18, operate as a high gain voltage amplifier between the input sensing node and a transistor M13 which acts as a source follower. The sensing device 100 also has a current mirror of two transistors M3 and M6, and an output stage
20 comprising two transistors M13 and M14. The sensor 12 is connected to the input of the amplifier M1 M4. The current source 18 is mirrored by the current mirror M6 M3 to provide the input current of the amplifier 14. The feedback transistor M2 is connected between the input and output of the amplifier M1 M4. The output of the amplifier M1 M4 is connected to the output stage M13
25 M14. Constant current load to the output of the amplifier M1 M4 is provided by transistors M5, M7 and M9. The current is also fed to the output stage at transistor M14. The output of the sensing device 100 is taken as a voltage from

the source of the other transistor M13 in the output stage. This is in contrast to the embodiment shown in Figure 3 in which the output current is taken from the drain of the transistor discriminator M8 in the output stage.

5 Feedback MOSFET transistor M2 is kept at a very low current, for example 1fA, that is, it is almost switched off, during the readout sequence and the integration of sensor charges into the input sensing node. The input-sensing node is floating during the integrating and readout time period, as the input current source is turned off at this time.

10 Once the sensor starts to supply sensor current, the negative feedback MOSFET M2 turns off, allowing the amplifier stage M1, M4 to go to an open-loop high gain state. During the integrating time period feedback MOSFET transistor M2 is OFF with an inverted polarity topology. A soft reset operation is then performed by applying an input DC current to the input current source 18, of
15 the order of 10pA, which biases feedback MOSFET transistor M2 in non-inverted polarity, and closes the loop on the non-linear transresistance amplifier M1M4. The floating diffusion of the sensor is then reset for the closed-loop DC potential of transconductance amplifier M1M4 without introducing kTC reset noise.

20

Figure 11 is a graph of the input current, one electron for each pulse, every 0.5 μ s, to the input node and of the output node of the sensor circuitry of Figure 10.

The operation of a sensing device of the type shown in Figures 2A, 3 and 10, at
25 cryogenic temperature improves circuit performance, as illustrated in Figure 12 which shows noise calculation as function of temperature. Cryogenic operation also improves charge collection of electrons in the silicon sensor layer by

increasing the carrier velocity and the minority carrier lifetime. Such operation also increases the sensitivity of the non-linear amplifier, and improves operating conditions of avalanche photodiodes.

- 5 Figure 13 shows simulations of the binary pixel circuit illustrated in Figure 3 with a 1.5fF sensor capacitance and designed in 0.25 μ m CMOS operating at liquid nitrogen temperature with a detection capability of 3 e-.

10 Figure 14 shows an array of sixteen pixels 10 of the type illustrated in Figure 3, forming a macropixel arrangement. The outputs of the plurality of pixel cells 10 are connected to a common high-speed bus 11, such as a Fast-OR bus line, to form a macro-pixel. The bus 11 also has a current source 120 to the output stages of the pixels 10.

- 15 The Fast-OR line is read out by a logic circuit that connects the OR signal to the peripheral end-of-logic column, as shown in Figure 4.

20 One example of a sensing device consists of pixel cells diffused into or otherwise formed on or in an ASIC silicon chip of the type shown in Figure 15 which comprises a substrate 200 and a passivation layer 210 on which are deposited metal contacts 215. A layer 218 of n-doped amorphous hydrogenated silicon(a-Si:H) is deposited over the metal contacts 215. A layer of intrinsic a-Si:H 220 is deposited onto the n-doped a-Si:H layer 218 and preferably covers the whole substrate 200. A thin p-doped layer 240 may be diffused into the
25 upper surface of the layer of intrinsic a-Si:H 220 and a top electrode pattern 250 is formed e.g. by deposition over the p-doped layer 240. The pattern may be common to all or at least a number of the pixels. A thickness of the a-Si:H

substrate 200 is 10 to 30 μm . The ASIC assembly has the typical thickness of a silicon wafer.

5 In alternative embodiments, other semiconductor materials than a-Si:H are used to form the pin structure, for example high atomic number materials such as selenium, lead iodide, cadmium telluride, mercuric iodide. These materials may be directly substituted for the a-Si:H in the structure shown in Figure 15. The detecting layer works by direct conversion and electrons are collected by the array of electrodes 215 of the ASIC and amplified and processed by the same
10 ASIC. Use of high atomic number materials is advantageous for high energy X-ray above 5KeV, where silicon does not have enough conversion efficiency. One deposition condition of high atomic number materials is a temperature deposition below 250 C to avoid to damage the underlying ASIC. This restricts the choice of possible detecting material.

15 For a-Si:H PIN detecting structure, the top electrode can be of ITO where visible light is to be detected. However other electrode materials may be used where X-rays or particles are to be detected.

20 Yet another example of a sensor integrated on the substrate which contains readout circuitry such as the amplifier, feedback circuitry and current mirror of Figures 2, 3 or 10, is shown in Figure 18. This sensor 500 is an avalanche photodiode structure on substrate 501, and consists of a p⁺ layer 502 over the substrate acting as anode contact, with an overlying neutral-charge depletion
25 region 503. A p layer 505 is formed in a well in the depletion region and is surrounded above and to its sides by an n layer 506, so that the p and n layers form a pn junction.. An oxide layer 508 provides a window for incoming

photons, and bias is supplied via a cathode connection 520 which may be a metallisation, a polysilicon line or otherwise as known to those skilled in the art. Other APD structures, for example including rings, can be used.

5 In another embodiment of the invention, in which the sensing device is a pixel sensor, an array of 64 pixels of the type shown in Figure 3 may be arranged to form a macropixel, as shown in Figures 16a and 16b. The macropixel 290 comprises an array of 64 pixels 300, each pixel 300 being connected to a bistable output circuit 310 which switches a current source into a common bus
10 320. The output of the bus 320 can then be multiplexed using a multiplexer 330 with the output of other similar arrays to build a large area detector. Once readout of the bus 320 is complete, the bistables 310 are reset.

Figure 17 shows a large area sensor 350, typically a complete wafer, carrying
15 an assembly of arrays 300 of the type shown in Figure 16a.

As mentioned above, in the embodiments illustrated in Figures 16a, 16b and 17, each pixel output 301 is connected to a separate bistable 310, one being allocated for each pixel. The output of each bistable 310 controls a current
20 source 315 which is connected to a local bus 320 connecting the pixels 300 to form a macropixel 290. When a hit generated by an X-Ray photon occurs, the bistable state of the bistable 310 connected to the pixel which has been hit switches to 1 and turns on the associated current source 315. Then, each time a hit occurs in the macropixel area, another bistable 310 will switch on
25 adding a current level to the macropixel bus 320. Once the readout time is over, the macropixel currents are readout as in standard analogue readout schemes of APS architecture, by analogue multiplexing. Once the readout is

finished, a global reset is applied to all pixel cells which switches back to zero the current level of the macropixel bus 320, and a next readout cycle can start again.

5 In binary schemes, such as that shown in Figure 4, the readout of individual pixels for pixel density of 1 million/cm² could cause serious problems. Furthermore, most of the medical applications need pixel dimensions of 50µm to 100µm, and not the 10µm pixel size of the pixels embodying the invention. The Applicant has appreciated that the aggregation of arrays of
10 pixels to form a macropixel 290 is a novel and inventive solution. The macropixel 400 illustrated in Figure 17 is particularly useful in HEP and medical applications and comprises a plurality of arrays of macropixels 290 incorporated into a wafer 400.

15 An additional advantage of forming a macropixel as described above and illustrated in Figure 16a, 1b and 17 is that it is possible to build a large area detector that may be incorporated into a wafer 410, as shown in Figure 17. The wafer 410 may be 8 inches in diameter with a 14cm square detector formed by the arrays of pixels 290. In this embodiment, an interconnecting
20 level may be added on top of the processed wafer before the amorphous Si:H deposition.

A further advantage of this embodiment is that whilst process defects may be present, which may be due to non-100% yield, they are localized in one pixel
25 thereby killing the functioning of that pixel, but not the macropixel itself. This results only in a loss of efficiency of the device but does not affect the ability of the device to perform its function. For an aggregation of 100 pixels of 10µm

in a macropixel of 100 μ m, one defect in the macropixel area of 100 μ m would decrease the efficiency only by 1%. Thus, even if a pixel is faulty, the macropixel device is still operable, albeit with a slight decrease in efficiency.

5 While the invention has been described in detail by specific reference to various embodiments, it is understood that variations and modifications may be made without departing from the true spirit and scope of the invention. In particular, the supply voltage may be varied. Also, advances in the semiconductor industry will provide, in the future, deeper submicron technologies for which
10 scaling rules should be applied to the invention described herein to benefit from smaller parasitic capacitance and obtain better circuit sensitivity and lower power consumption. Scaling of the very deep submicron future CMOS technologies will increase circuit sensitivity of the invention that will make possible single electron signal amplification and discrimination.

15 Furthermore, it will be appreciated that the values given above in the description of the embodiments are based on idealised circuit operation during computer simulation and for a given deep submicron CMOS technology, and that therefore relatively minor variations will not substantially affect the
20 operation of the circuits illustrated in the accompanying Figures 2A to 4, 10 and 16a.

In summary, the present invention is applicable to the field of solid state radiation sensors, monolithic integration of active pixel sensors (APS), and
25 more specifically to the field of imaging and Single Photon Detection and Single Particle Detection (SPD). An Active Pixel Sensor (APS) signal processing circuit is described for covering multi-electron level signals

delivered by a pixel radiation sensor integrated in a monolithic integrated circuit designed with commercial deep submicron CMOS technologies. The readout circuit is an Application Specific Integrated Circuit (ASIC) that performs fast signal amplification and fast signal discrimination with a 12 MOSFET transistor
5 250nW circuit cell that is associated with each pixel radiation sensor. Each pixel sensor consists either of a p-n junction built in the bulk of the silicon substrate or of a PIN diode built in a thin film of hydrogenated amorphous silicon deposited on the top of the ASIC. The readout pixel circuit provides a fast logic signal or a fast analogue signal each time a photon or a charged
10 particle impinges on the radiation pad sensor. This is accomplished without any additional peripheral processing circuit.

Furthermore, one or more embodiments of the invention are capable of single particle detection (SPD), and effectively operate as a quantum device by
15 detecting each incident quantum individually. The embodiments of the invention are very sensitive devices which are compact and operate at extremely low power.

A variant of the circuit works by integration as for standard APS, but with an
20 internal pixel gain of about 1000. Several readout pixel circuits with their associated pixel sensors of typical size ranging from $5\mu\text{m} \times 5\mu\text{m}$ to $30\mu\text{m} \times 30\mu\text{m}$ can be grouped together via a single analogue or a digital bus line to form a macropixel dimensioned to fit the required space resolution and desired pixel shape. Each macropixel information, binary or analogue can be retrieved
25 individually with a synchronous readout with addressable column logic or with asynchronous column logic, or with an analogue multiplexer like in standard CMOS APS imagers.

Having described various embodiments of this invention, it will be now apparent to one of ordinary skill in the art that other embodiments incorporating the concept may be used. Therefore, the invention should not be limited to the disclosed embodiment, but rather should be limited only by the following
5 appended claims.

I. Glossary of Symbols

- 5 • kTC noise, also termed reset noise is the noise associated with the reset operation in APS circuits, CMOS imagers and CCD devices. In reference to the Fig.1 Prior art, each time the readout cycle is completed the input sensing node of S, gate of M1 is reset by the transistor reset switch M2 to a reference voltage that is applied to the gate of M2. This operation generates a noise at the input sensing node, the gate of M1, equal to $v_n^2 = \frac{kT}{C_{IN}}$, where C_{IN} is the input capacitance. V_n increases when C_{IN} decreases. This causes

10 serious problems in a high density APS pixel circuit. An embodiment of the present invention aims to solve this problem by aiming to eliminate reset noise.
- 15 • ENC (ENC_p for parallel noise ENC_s for series noise): Equivalent Noise Charge, it is the r.m.s. charge usually expressed in electron r.m.s. that should be applied at the input of the amplifying channel to obtain the same output noise caused by the internal physical noise sources of this amplifying channel. The ratio of the input signal/ENC gives the signal-to-noise ratio, a basic number of the channel sensitivity.
- 20 • $U_T = \frac{kT}{q}$ is the thermal voltage about 25.6 mV, here K is the Boltzman constant $1.381 \cdot 10^{-23}$ Joule/Kelvin, T is the absolute temperature in Kelvin (300K for room T), q is the electronic charge $1.602 \cdot 10^{-19}$ C

- C_{ox} is the unit capacitance of the gate oxide of the MOS transistor. Typically, it is $5\text{fF}/\mu\text{m}^2$ for quarter micron CMOS technology used for in an embodiment of the present invention.
- C'_{ox} is the gate oxide capacitance per unit area of the MOS transistor. It is $5\text{fF}/\mu\text{m}^2$ in the quarter micron CMOS technology used in an embodiment of the present invention. The sign " ' " means a normalized unit.
- n is the slope factor of the MOS transistor equal to
$$n = 1 + \frac{\gamma}{2\sqrt{\Psi_0 + V_p}}$$
 with the surface potential $\Psi_0 \approx 2\Phi_F + 3U_T$ where Φ_F is the fermi potential, and $\gamma = \sqrt{\frac{2q\epsilon_{si}N_{SUB}}{C_{ox}'}}$ where N_{SUB} is the substrate doping concentration ϵ_{si} the silicon permittivity $1.04 \cdot 10^{-11}$ F/m, and V_p is the pitch off voltage of the MOS transistor
- μ is the carrier mobility
- W is the gate width of the MOS transistor defined by design
- L is the gate length of the MOS transistor defined by design
- C_{OUT} is the output capacitance of the output node of an embodiment of the present invention, at the interconnection of the input branch with the load branch.
- C_{IN} is the capacitance of the input sensing node
- V_T is the threshold voltage of the MOS transistor

- gm (also gm_f and gm_i) is the transconductance of the MOS transistor, gate transconductance in weak inversion is

$$gm = \frac{I_D}{nU_T}, \text{ source transconductance is } gms = \frac{I_D}{U_T}$$

- T_m is the pulse shaping peaking time of the amplifying channel

5

II. Glossary of terms and labeling of components in figures

T1 Feedback transistor in fig.2B

T2 Input current source in fig.2B

10

T3 Current mirror controlling T2 in fig.2B

T4 Discriminator transistor in fig.2B

M1 Input transistor in fig.3

M2 Feedback transistor in fig.3

M3 Input current source in fig.3

15

M4 Cascode transistor of the input branch in fig.3

M5 Load branch in fig.3

M6 Current mirror controlling input current source M3 in fig.3

M7 Cascode transistor of the output load branch in fig.3

M8 Discriminator transistor branch X

20

M9 Bias current mirror transistor of the load branch

M10 Cascode transistor branch X

M11 Discriminator transistor branch Y

M12 Cascode transistor branch Y

M13 is the output source follower transistor of fig.10

M14 is the output current source of fig.10

- 5
- Pixel sensor cell 12 is the generic name for the four sensor types (a-Si:H P-I-N diode, P-N diffused junction, APD P-N diffused junction, and amorphous Selenium layer)
 - Input sensing node, referring to Fig 3 Binary architecture, it consists of the common interconnection of N-electrode of the pixel sensor cell with drain of the input current source M3, gate of the input transistor M1, drain of the feedback transistor M2.
- 10
- Input branch is transistors M1-M4
 - Load branch is transistors M5-M7
 - Discriminator output branch X is transistor M8-M10
- 15
- Discriminator output branch Y is transistor M11-M12
 - V_{REF} Reference Voltage in Fig.2A, Fig.2B and Fig3 defines the operating point of the output branches X and Y
 - I_{REF} is the reference current in Fig.2A, Fig.2B and Fig 3
 - I_{BIAS} is the Bias current of the bias input branch and load branch via the mirror transistor M9
- 20
- Q_{DET} is the input charge generated by a particle hit in the pixel sensor cell.

- I_{DO} is the standing current in the input branch and load branch almost equal to the bias current (mirror current).